X-ray / optical correlations in the transient black hole system KV UMa (J1118+48)

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H. Steinle, MPE, AG Tagung Berlin, Splinter Meeting on Active Black Holes; September 26, 2002

The year 2000 transient: XTE J1118+48 (=KV UMa)

- transient X-ray source during Jan – Jul 2000
- nearby object (~ 2 kpc) at high galactic latitude
- \cdot estimated mass of compact star > 6 M $_{\odot}$
- Hard spectral state with high variability
- high optical / X-ray luminosity ratio



Correlated observations using a RXTE-PCA ToO program and OPTIMA from Skinakas observatory, Crete were carried out during July 4-8, 2000 A total of <u>2.5 hours</u> of coincident measurements were performed!

(Kanbach, Straubmeier, Spruit, and Belloni, 2001, Nature **414**, 180)

Optical-EUV-X-ray spectrum



High optical / X-ray luminosity ratio!

Data from April 18, 2000

EUVE data from April 16, 2000

McClintock et al., 2001, ApJ, 555, 477

XTE J1118+48 (KV UMa)

 $L_{opt-EUV} \sim 10^{36} \text{ erg s}^{-1} > L_X \Rightarrow \text{variable optical radiation can <u>not</u> be reprocessed X-rays Synchrotron emission?$

- steep turn-over of spectrum at EUV is hard to explain with non-thermal synchrotron emission
- \cdot a thermal cyclo-synchrotron emission is more likely with T_e \sim 200 keV, B~10^6 G, optical thickness up to \sim 100



RXTE and OPTIMA Lightcurves



Mean X-Ray and **Optical** "Flares" (~100)



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'Reprocessing' or 'Light-Echoes'



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X-ray optical correlations



Positive correlation with short rise (~ 100ms) Maximum at ~ 500 ms; length ~ 5 sec; onset of sharp rise within 30 ms of X-ray peak;

Anti-correlation at -2 sec: precognition dip



Autocorrelation Functions



Time scales of the optical emission are much shorter than at X-rays. This is inconsistent with a reprocessing scheme!



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New Analysis

Principal Components Analysis

(Spruit & Kanbach A&A **391**, 225-233, 2002)

Analysis of 250 events +/- 100 s_ results in 2 independent components:



no time-of-flight effect? both dip and peak are properties of optical light

Shot Analysis

(Malzac et al. Proc. Cargese WS "Black Holes", 2002)

- analysis of different (RXTE) X-ray spectral bands
 - events similar in all spectral bands and correlated with optical; anticorrelation of X-ray flux and hardnes ratio
- separate analysis of strong and weak events (shots)
 - 🔶 events similar
 - Conclusion: one emission process that creates X-ray and optical emission. Similar structure on different time scales.

Optical emission from slow outflow



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Origin of Optical-EUV spectrum (continuum with weak lines)

 $\label{eq:Lopt-EUV} $L_{x} \Rightarrow variable optical radiation can not} \\ be reprocessed X-rays$

Synchrotron emission?

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